

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Reliability testing – Compliance tests for constant failure rate and constant failure intensity

Essais de fiabilité – Plan d’essais de conformité d’un taux de défaillance constant et d’une intensité de défaillance constante



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INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX

XF

ICS 03.120.30; 19.020; 21.020

ISBN 978-2-88912-061-1

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**RELIABILITY TESTING –
COMPLIANCE TESTS FOR CONSTANT FAILURE RATE
AND CONSTANT FAILURE INTENSITY**

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International Standard IEC 61124 has been prepared by IEC technical committee 56: Dependability.

This third edition of IEC 61124 cancels and replaces the second edition, published in 2006, and constitutes a technical revision.

The main changes with respect to the previous edition are as follows:

- A number of new test plans have been added based on the Russian standard GOST R 27.402 [1]¹, and it is intended to align the new edition of MIL-HDBK-781 [2] with this edition. Algorithms for optimizing test plans using a spreadsheet program are given and a number of optimized test plans are listed. Furthermore, emphasis is laid on the fact that the test should be repeated following design changes.

¹ Figures in square brackets refer to the bibliography.

- Discrepancies in test plans A, B as well as Annexes A and B that originated in IEC 60605-7 [3], now withdrawn, have been corrected so these test plans differ from those given in previous editions of IEC 61124. As requested by the National Committees, mathematical background material and spreadsheet program information has been moved to informative annexes. In addition, the symbol lists have been divided, so that some annexes have separate lists of symbols.
- Guidance on how to choose test plans has been added as well as guidance on how to use spreadsheet programs to create them. Test plans A.1 to A.9 and B.1 to B.13 have been corrected.
- Subclauses 8.1, 8.2, 8.3, Clause 9, Annex C, Clauses G.2, I.2, I.3 and Annex J are unchanged, except for updated terminology and references.
- Corrections to the second edition proposed by National Committees have been implemented.

The text of this standard is based on the following documents:

FDIS	Report on voting
56/1461/FDIS	56/1468/RVD

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The contents of the corrigendum of January 2013 have been included in this copy.

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